	Application/Control No.	Applicant(s)/Patent Under Reexamination
Issue Classification	10612866	KOLEK ET AL.
	Examiner	Art Unit
	Tran, Len	1725

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	ORIGINAL	NAL	INI	INTERNATIONAL CLASSIFICATION	CLASSIFICAT	NOI	
	CLASS	SUBCLASS	CLAIMED	٥	ON	NON-CLAIMED	Τ
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(Legal Instruments Examiner)		(Primary Examine)	(Date)		-	50	
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